

ABSTRACT OF DISCLOSURE

An inspecting apparatus for semiconductor devices comprising: a match plate; a contact module combined with the match plate, itself comprising a radiator to radiate heat from the semiconductor device to the outside and a tester to contact the leads of the semiconductor device; and a heat pipe provided in the radiator. Accordingly, the inspecting apparatus for semiconductor devices according to the present invention performs testing at a constant temperature, regardless of heat from the semiconductor device, by transferring heat from the semiconductor device quickly and efficiently, thereby producing more accurate test results.

The inspecting apparatus for semiconductor devices according to the present invention improves productivity and saves expense by removing faulty test results caused by incorrectly identifying qualified semiconductor devices as defective semiconductor devices.